

1. Record Nr.	UNINA9910827817203321
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Titolo	Structure analysis of advanced nanomaterials : nanoworld by high-resolution electron microscopy // Takeo Oku
Pubbl/distr/stampa	Berlin, [Germany] ; ; Boston, [Massachusetts] : , : De Gruyter, , 2014 ©2014
ISBN	1-5231-0054-0 3-11-038804-9
Descrizione fisica	1 online resource (180 p.)
Disciplina	502.825
Soggetti	Transmission electron microscopy High resolution electron microscopy Nanostructured materials Structural analysis (Engineering)
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Description based upon print version of record.
Nota di bibliografia	Includes bibliographical references at the end of each chapters and index.
Nota di contenuto	Front matter -- Preface -- Contents -- 1 Introduction -- 2 Structure and principle of electron microscopes -- 3 Practice of HREM -- 4 Characterization by HREM -- 5 Electron diffraction analysis of nanostructured materials -- 6 HREM analysis of nanostructured materials -- A Appendix -- Index
Sommario/riassunto	High-resolution electron microscopy allows the imaging of the crystallographic structure of a sample at an atomic scale. It is a valuable tool to study nanoscale properties of crystalline materials such as superconductors, semiconductors, solar cells, zeolite materials, carbon nanomaterials or BN nanotubes.